

Search Notes

Application/Control No.

10/575,545

Examiner

Hien D. Vu

Applicant(s)/Patent under
Reexamination

VAN MEIJL ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
439	362,364, 607,677, 953	9/24/2007	HV
Updated	Search	6/15/2008	HV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR